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54ABT16500 18-Bit Universal Bus Transceivers with TRI-STATE Outputs

# 54ABT16500 18-Bit Universal Bus Transceivers with TRI-STATE® Outputs

### **General Description**

These 18-bit universal bus transceivers combine D-type latches and D-type flip-flops to allow data flow in transparent, latched, and clocked modes.

Data flow in each direction is controlled by output-enable (OEAB and  $\overline{\text{OEBA}}$ ), latch-enable (LEAB and LEBA), and clock ( $\overline{\text{CLKAB}}$  and  $\overline{\text{CLKBA}}$ ) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if  $\overline{\text{CLKAB}}$  is held at a high or low logic level. If LEAB is low, the A bus data is stored in the latch/flip-flop on the high-to-low transition of  $\overline{\text{CLKAB}}$ . Output-enable OEAB is active-high. When OEAB is high, the outputs are active. When OEAB is low, the outputs are in the high-impedance state.

Data flow for B to A is similar to that of A to B but uses  $\overline{\text{OEBA}}$ , LEBA, and  $\overline{\text{CLKBA}}$ . The output enables are complementary (OEAB is active high and  $\overline{\text{OEBA}}$  is active low).

To ensure the high-impedance state during power up or power down, OE should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

#### **Features**

- Combines D-Type latches and D-Type flip-flops for operation in transparent, latched, or clocked mode
- Flow-through architecture optimizes PCB layout
- Guaranteed latch-up protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Standard Microcircuit Drawing (SMD) 5962-9687001

### **Ordering Code**

Military	Package Number	Package Description
54ABT16500W-QML	WA56A	56-Lead Cerpack

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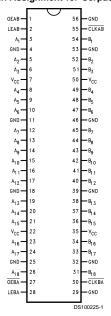
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# **Connection Diagram**

#### Pin Assignment for Cerpack



# Function Table (Note 1)

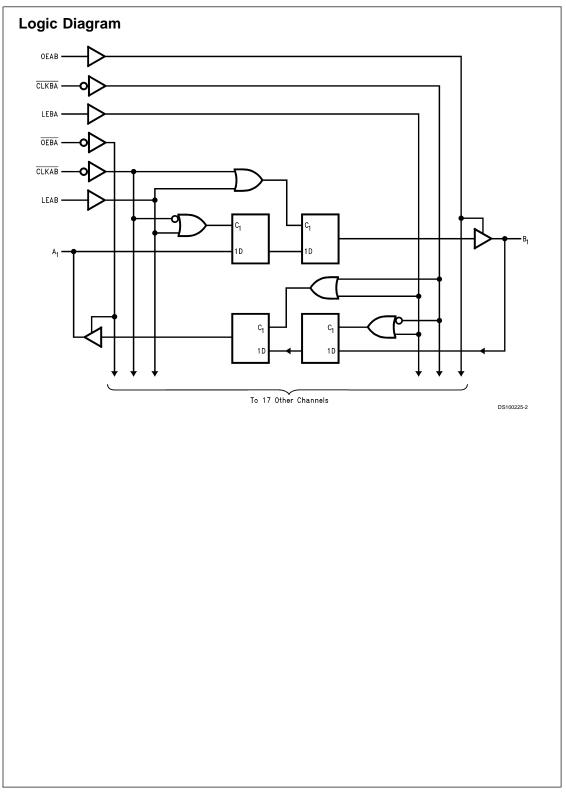
	Inp	Output		
OEAB LEAB C		CLKAB	Α	В
L	Х	X X		Z
н н		X	L	L
Н	H H X H L ↓ H L ↓ H L H		Н	Н
Н			L	L
Н			Н	Н
Н			Χ	B <sub>0</sub> (Note 2)
Н			X	B <sub>o</sub> (Note 3)

 $\textbf{Note 1:} \ \, \text{A-to-B data flow is shown: B-to-A flow is similar but uses } \overline{\text{OEBA}}, \, \text{LEBA, and } \overline{\text{CLKBA}}.$ 

Note 2: Output level before the indicated steady-state input conditions were established.

Note 3: Output level before the indicated steady-state input conditions were established, provided that CLKAB was low before LEAB went low.





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### **Absolute Maximum Ratings** (Note 4)

Storage Temperature -65°C to +150°C Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias

-55°C to +175°C Ceramic

V<sub>CC</sub> Pin Potential to

Ground Pin -0.5V to +7.0V Input Voltage (Note 4) -0.5V to +7.0VInput Current (Note 4) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-off State -0.5V to 5.5V in the HIGH State -0.5V to  $V_{\mbox{\scriptsize CC}}$ 

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) DC Latchup Source Current -500 mA Over Voltage Latchup (I/O)

10V

### **Recommended Operating** Conditions

Free Air Ambient Temperature

Military -55°C to +125°C

Supply Voltage

Military +4.5V to +5.5V Minimum Input Edge Rate  $(\Delta V/\Delta t)$ Data Input 50 mV/ns Enable Input 20 mV/ns

Note 4: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 5: Either voltage limit or current limit is sufficient to protect inputs.

### **DC Electrical Characteristics**

Symbol	Parameter		ABT16500		Units	V <sub>CC</sub>	Conditions	
			Min	Тур	Max			
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	V <sub>IL</sub> Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	/ <sub>CD</sub> Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	54ABT	2.5			V	Min	I <sub>OH</sub> = -3 mA
		54ABT	2.0			V	Min	I <sub>OH</sub> = -24 mA
$V_{OL}$	Output LOW Voltage	54ABT			0.55	V	Min	I <sub>OL</sub> = 48 mA
I <sub>IH</sub>	Input HIGH Current				5	μA	Max	V <sub>IN</sub> = 2.7V (Note 6)
					5			V <sub>IN</sub> = V <sub>CC</sub>
I <sub>BVI</sub>	Input HIGH Current Breakdown Te	est			7	μA	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current				-5	μA	Max	V <sub>IN</sub> = 0.5V (Note 6)
					-5			V <sub>IN</sub> = 0.0V
$V_{ID}$	Input Leakage Test		4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
								All Other Pins Grounded
I <sub>IH</sub> +	Output Leakage Current				50	μA	0 - 5.5V	V <sub>OUT</sub> = 2.7V; <del>OE</del> , OE = 2.0V
$I_{OZH}$								
I <sub>IL</sub> +	Output Leakage Current				-50	μA	0 - 5.5V	V <sub>OUT</sub> = 0.5V; <del>OE</del> , OE = 2.0V
$I_{OZL}$								
los	Output Short-Circuit Current		-100		-275	mA	Max	V <sub>OUT</sub> = 0V
I <sub>CEX</sub>	Output High Leakage Current  Bus Drainage Test  Power Supply Current  Power Supply Current				50	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>					100	μA	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>					1.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>					68	μA	Max	An or Bn Outputs Low
I <sub>CCZ</sub>	Power Supply Current				1.0	mA	Max	$\overline{OE}_n = V_{CC}$
								All Others at V <sub>CC</sub> or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input				2.5	mA	Max	V <sub>I</sub> = V <sub>CC</sub> - 2.1V
								All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/	Max	Outputs Open
	(Note 6)				0.23	MHz		Transparent Mode
								One Bit Toggling, 50% Duty Cycle

Note 6: Guaranteed, but not tested.

#### **DC Electrical Characteristics** Symbol Parameter Min Max Units Conditions $C_L = 50 pF; R_L =$ $\mathbf{500}\Omega$ Quiet Output Maximum Dynamic V<sub>OL</sub> ٧ $T_A = 25^{\circ}C \text{ (Note 7)}$ $V_{\mathsf{OLP}}$ 1.1 5.0 Quiet Output Minimum Dynamic V<sub>OL</sub>

-1.7

5.0

 $T_A = 25^{\circ}C$  (Note 7)

Note 7: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

# **AC Electrical Characteristics**

 $V_{\mathsf{OLV}}$ 

Symbol	Parameter	54ABT		Units	Fig.
		~	to +125°C		No.
		$V_{CC} = 4.5V - 5.5V$ $C_1 = 50 \text{ pF}$			
		Min	Max	1	
f <sub>max</sub>	Maximum Clock Frequency	150		MHz	
t <sub>PLH</sub>	Propagation Delay	1.0	6.5	ns	Figure 4
t <sub>PHL</sub>	A or B to B or A	1.0	7.0		
t <sub>PLH</sub>	Propagation Delay	1.0	7.0	ns	Figure 4
t <sub>PHL</sub>	LEAB or LEBA to B or A	1.0	7.8		
t <sub>PLH</sub>	Propagation Delay	1.0	7.5	ns	Figure 4
t <sub>PHL</sub>	CLKAB or CLKBA to B or A	1.0	8.0		
t <sub>PZH</sub>	Propagation Delay	1.0	6.3	ns	Figure 6
t <sub>PZL</sub>	OEAB or OEBA to B or A	1.0	6.5		
t <sub>PHZ</sub>	Propagation Delay	1.0	7.2	ns	Figure 6
t <sub>PLZ</sub>	OEAB or OEBA to B or A	1.0	6.8		

# **AC Operating Requirements**

Symbol	Parameter	54ABT		Units	Fig.
		$T_A = -55^{\circ}C$	C to +125°C		No.
		V <sub>CC</sub> = 4	.5V-5.5V		
		C <sub>∟</sub> = 50 pF			
		Min	Max		
t <sub>s</sub> (H)	Setup Time,	4.5		ns	Figure 7
t <sub>s</sub> (L)	A to CLKAB	4.5			
t <sub>h</sub> (H)	Hold Time,	0		ns	Figure 7
$t_h(L)$	A to CLKAB	0			
t <sub>s</sub> (H)	Setup Time,	4.0		ns	Figure 7
$t_s(L)$	B to CLKBA	4.0			
t <sub>h</sub> (H)	Hold Time,	0		ns	Figure 7
t <sub>h</sub> (L)	B to CLKBA	0			
t <sub>s</sub> (H)	Setup Time, A to LEAB	1.5		ns	Figure 7
$t_s(L)$	or B to LEBA, CLK High	1.5			
t <sub>h</sub> (H)	Hold Time, A to LEAB	1.5		no	Figure 7
t <sub>h</sub> (L)	or B to LEBA, CLK High	1.5		ns	
t <sub>s</sub> (H)	Setup Time, A to LEAB	4.5		ns	Figure 7
t <sub>s</sub> (L)	or B to LEBA, CLK Low	4.5			
t <sub>h</sub> (H)	Hold Time, A to LEAB	1.5		ns	Figure 7
$t_h(L)$	or B to LEBA, CLK Low	1.5			
t <sub>w</sub> (H)	Pulse Width,	3.3		ns	Figure 5
$t_w(L)$	LEAB or LEBA, High	3.3			

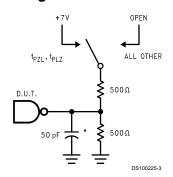
AC Operating Requirements (Continued)							
Symbol	Parameter	54/	ABT	Units	Fig.		
		$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_L = 50 \text{ pF}$			No.		
		Min	Max				
t <sub>w</sub> (H)	Pulse Width, CLKAB	3.3		ns	Figure 5		
$t_w(L)$	or CLKBA, High or Low	3.3					

# Capacitance

Symbol	Parameter	Тур	Units	Conditions, T <sub>A</sub> = 25°C	
C <sub>IN</sub>	Input Capacitance	5.0 pF		$V_{CC} = 0.0V$	
C <sub>I/O</sub> (Note 8)	Output Capacitance	11.0	pF	V <sub>CC</sub> = 5.0V	

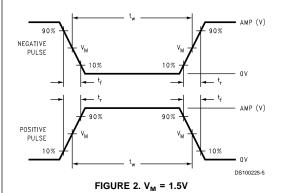
Note 8: C<sub>I/O</sub> is measured at frequency f = 1 MHz per MIL-STD-883B, Method 3012.

# **AC Loading**



\*Includes jig and probe capacitance.

FIGURE 1. Standard AC Test Load



Input Pulse Requirements

Amplitude	Rep. Rate	t <sub>w</sub>	t <sub>r</sub>	t <sub>f</sub>			
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns			

FIGURE 3. Test Input Signal Requirements

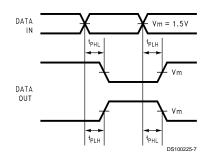


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

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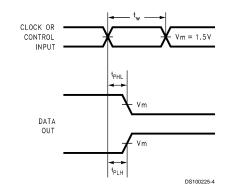


FIGURE 5. Propagation Delay, Pulse Width Waveforms

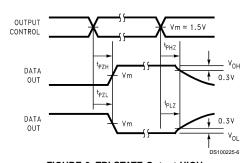


FIGURE 6. TRI-STATE Output HIGH and LOW Enable and Disable Times

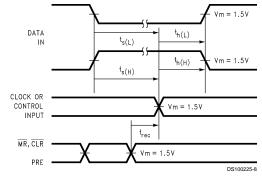
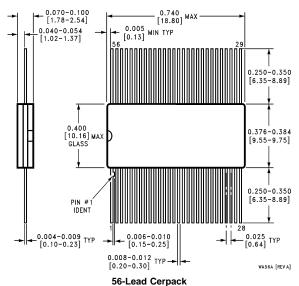


FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms



# NS Package Number WA56A

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